Notice of References Cited

Application/Control No.

O9/768,454

Examiner

Justin P Misleh

Applicant(s)/Patent Under
Reexamination
FUKUYOSHI ET AL.

Art Unit
Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	Α	US-6,271,103 B1	08-2001	Lee, Chun Tak	438/464
	В	US-6,043,481	03-2000	Tan et al.	250/216
	С	US-6,069,350 C	05-2000	Ohtsuka et al.	250/208.1
	D	US-6,163,407 C	12-2000	Okazaki et al.	359/619
	E	US-6,583,438 B1 <	06-2003	Uchida, Shinji	257/59
	F	US-5,583,354 ~	12-1996	Ishibe, Shouichi	257/232
	G	US-6,639,726 B1 /	10-2003	Campbell, Scott Patrick	359/619
	Н	US-6,414,343 B1 <	07-2002	Kondo et al.	257/294
	1	US-6,307,243 B1	10-2001	Rhodes, Howard E.	257/432
	J	US-6,188,094 B1	02-2001	Kochi et al.	257/232
	К	US-5,239,412 ,	08-1993	Naka et al.	359/619
	L	US-			
	М	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N	JP 05145813 A 🗸	06-1993	Japan	ISOKAWA, TOSHIHIKO	H04N 05/225
	0					
	Р					
	Q					
	R					
	s					
	Т					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)						
	כ							
	>							
	8							
	x							

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).) Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.

